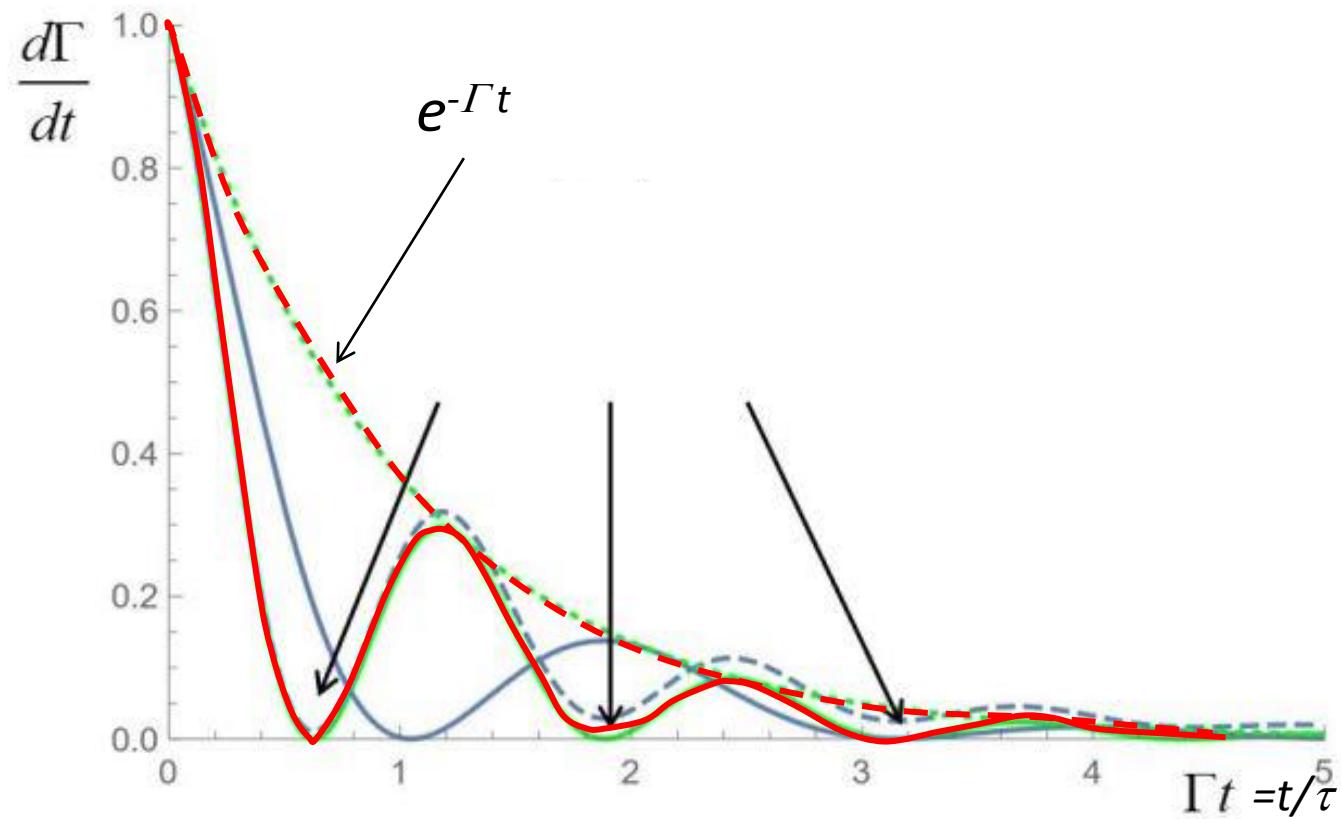
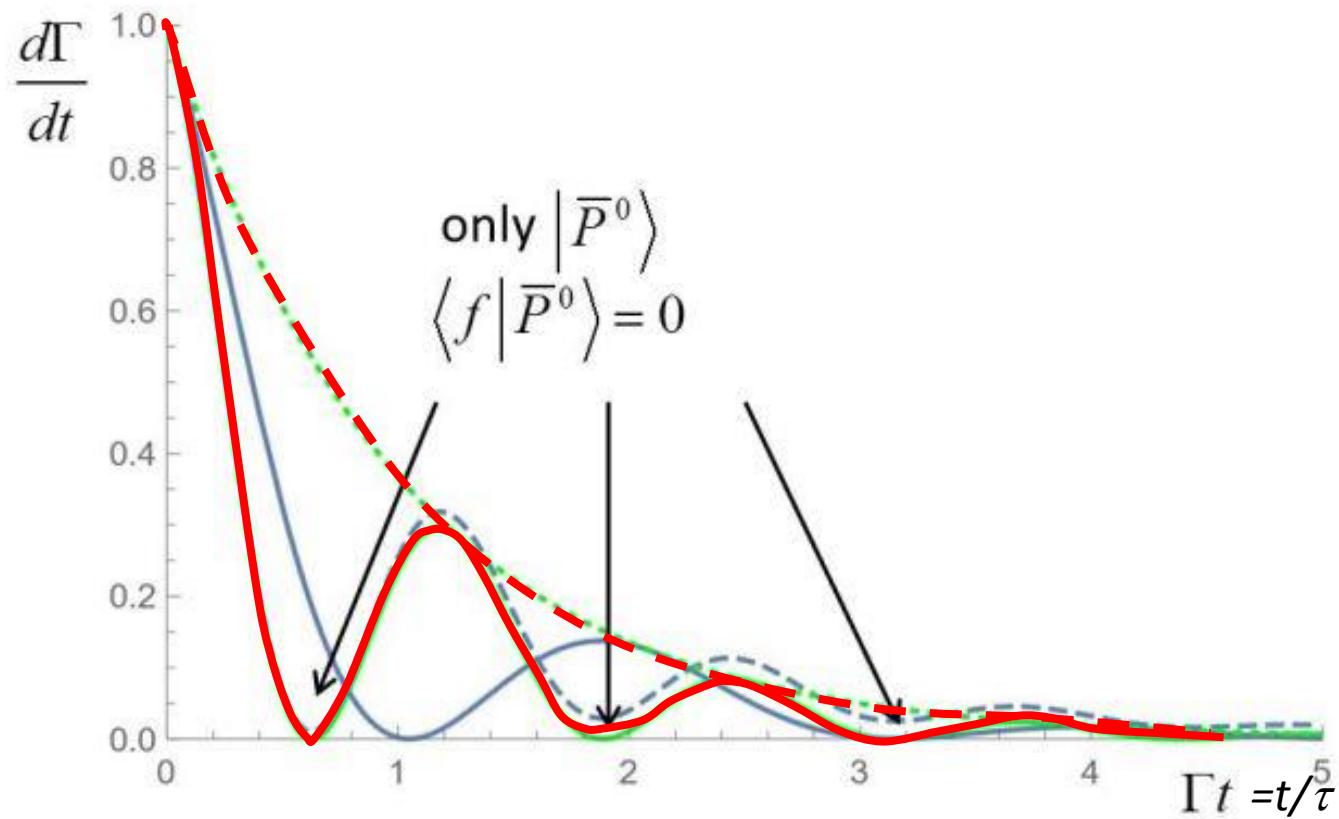


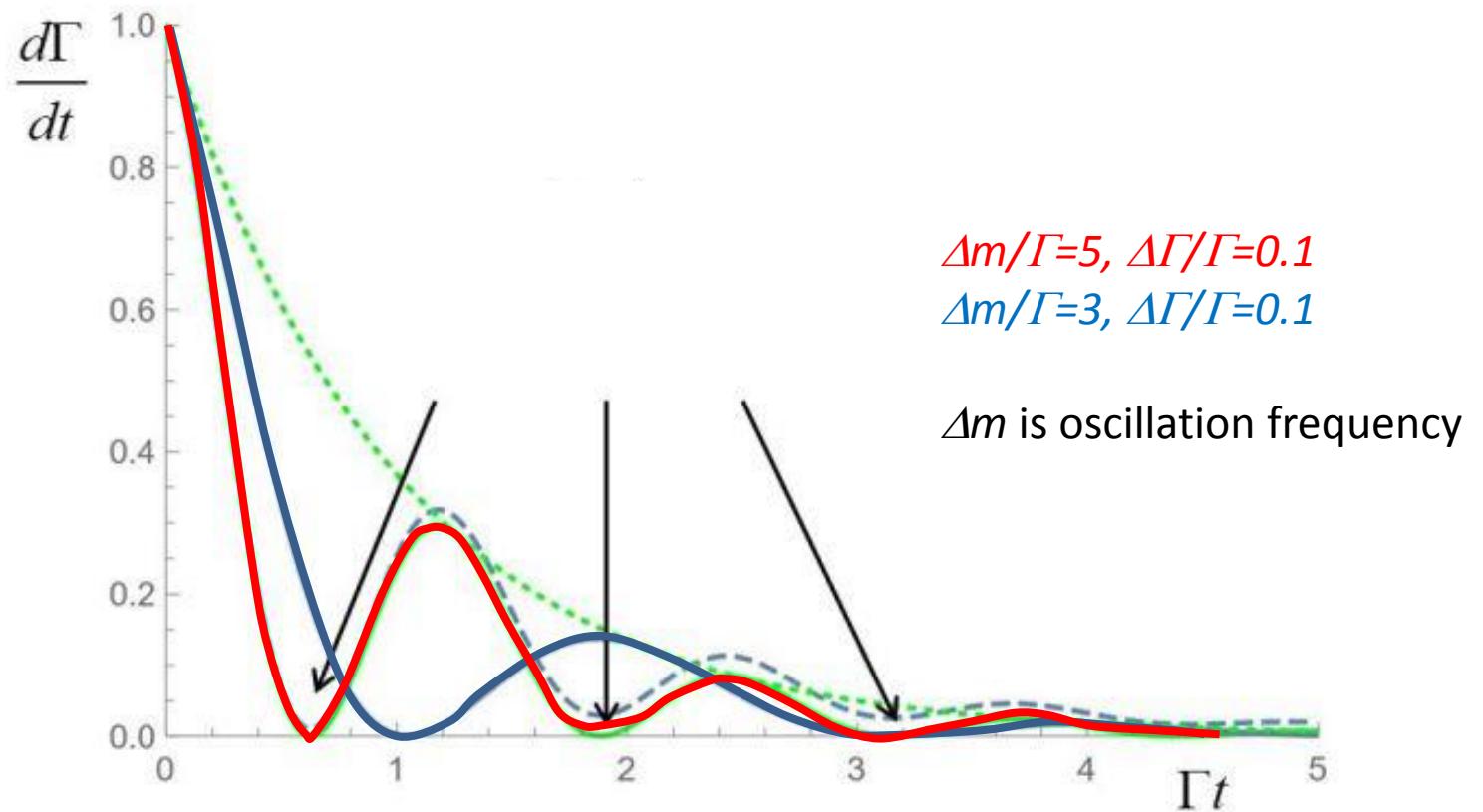
$$\frac{d\Gamma(P^0 \rightarrow f)}{dt} = \mathcal{N}_+ e^{-\Gamma t} [\cosh\left(\frac{\Delta\Gamma t}{2}\right) + \cos(\Delta m t)] |\langle f | P^0 \rangle|^2$$



$$\frac{d\Gamma(P^0 \rightarrow f)}{dt} = \mathcal{N}_+ e^{-\Gamma t} [\cosh\left(\frac{\Delta\Gamma t}{2}\right) + \cos(\Delta m t)] |\langle f | P^0 \rangle|^2$$



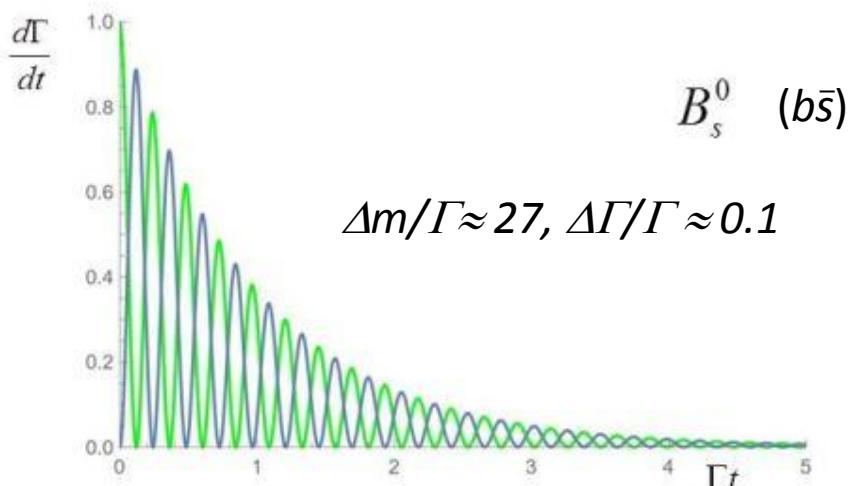
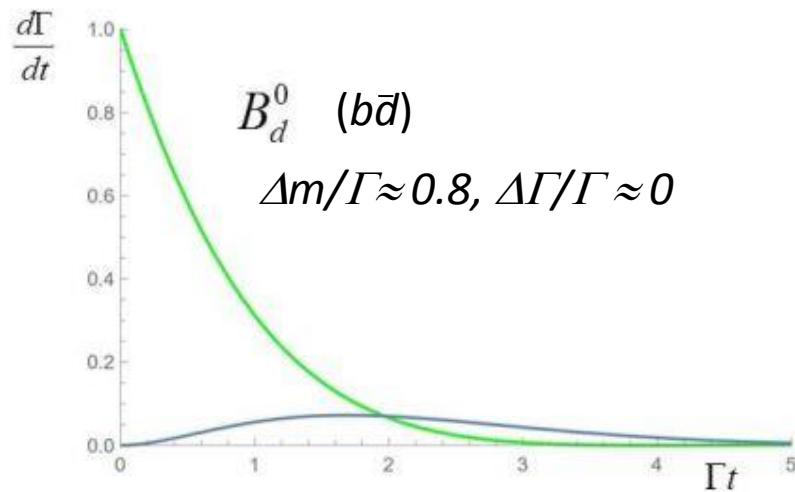
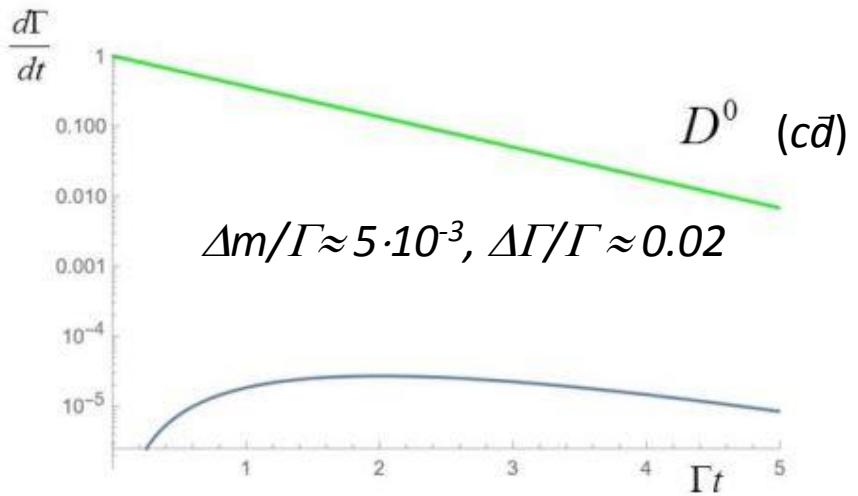
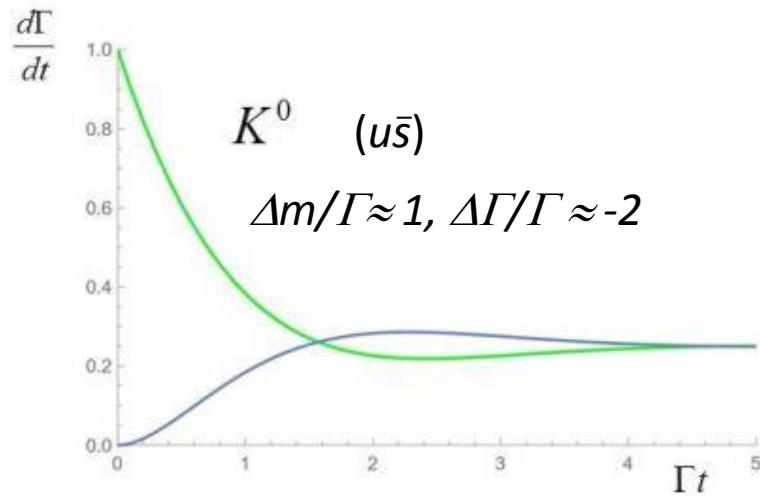
$$\frac{d\Gamma(P^0 \rightarrow f)}{dt} = \mathcal{N}_+ e^{-\Gamma t} [\cosh\left(\frac{\Delta\Gamma t}{2}\right) + \cos(\Delta m t)] |\langle f | P^0 \rangle|^2$$

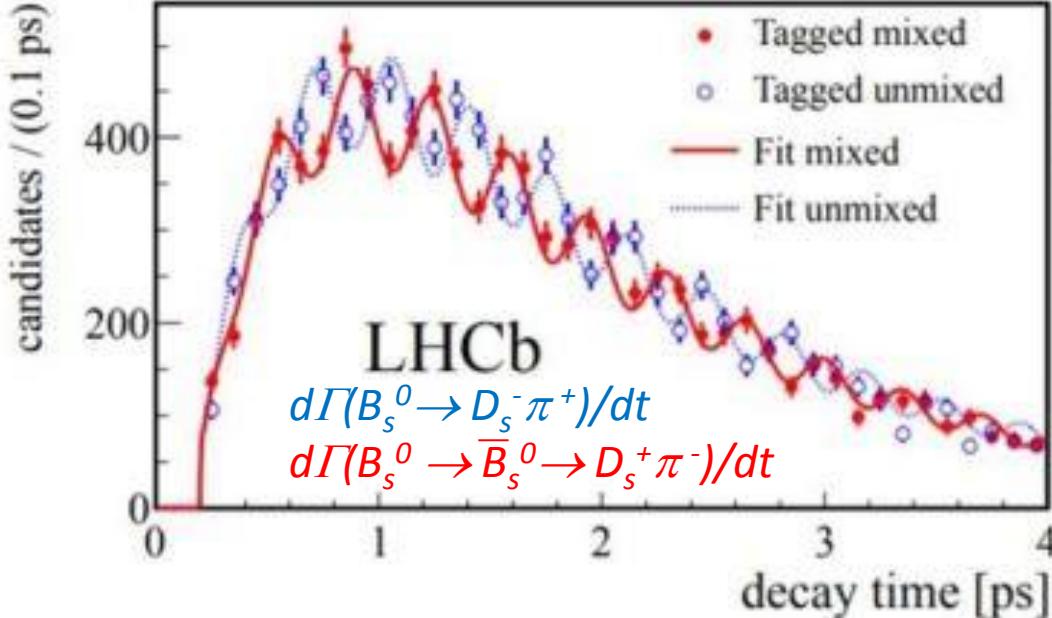


$$d\Gamma(P^0 \rightarrow f)/dt$$

for an initially produced  $P^0$

$$d\Gamma(\bar{P}^0 \rightarrow \bar{f})/dt$$

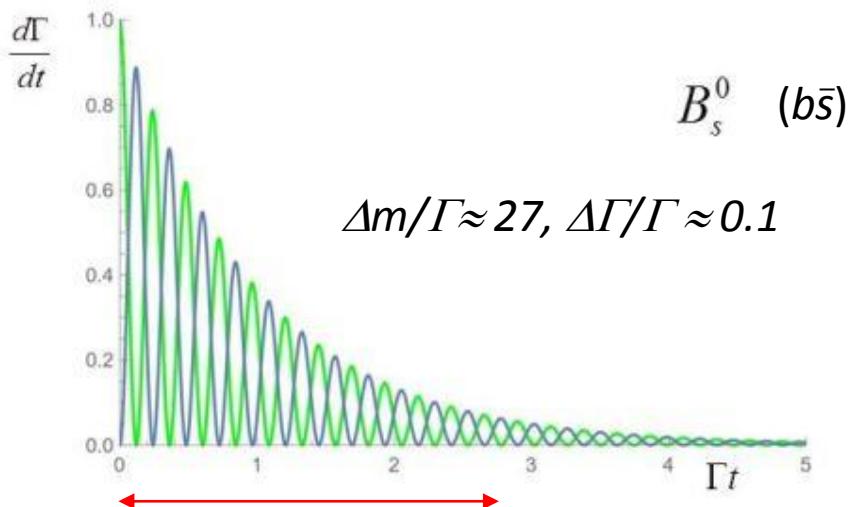


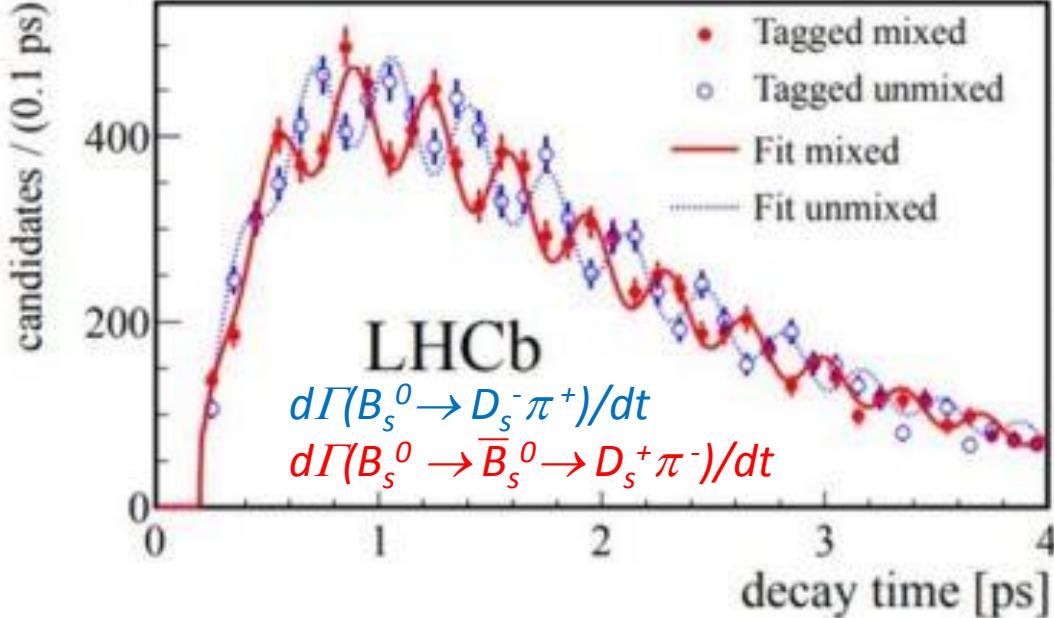


actual measurement

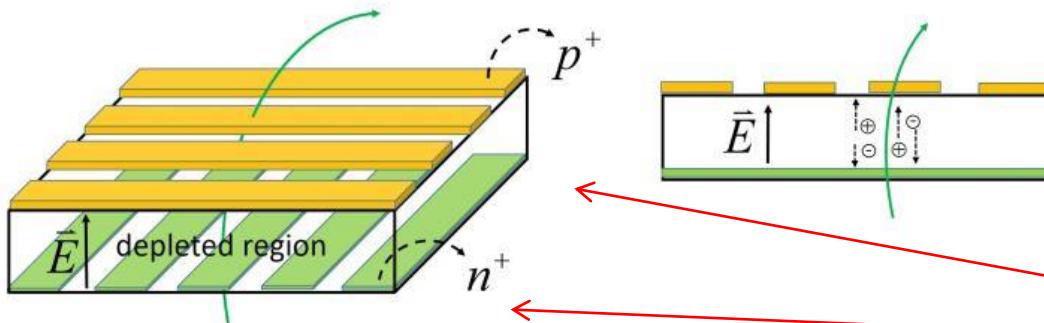
$\xleftarrow{\hspace{-1cm}} \xrightarrow{\hspace{-1cm}} d\Gamma(P^0 \rightarrow f)/dt$  for an initially produced  $P^0$

$d\Gamma(\bar{P}^0 \rightarrow \bar{f})/dt$





actual measurement



semiconductor detectors

$$\sigma(r,\phi) \sim \mathcal{O}(10 \mu\text{m})$$



$$\mathcal{A}_{\text{flav}} = \frac{(N_{\text{unmix}}(t) - N_{\text{mix}}(t))}{(N_{\text{unmix}}(t) + N_{\text{mix}}(t))} = \frac{\cos(\Delta mt)}{\cosh\left(\frac{\Delta\Gamma t}{2}\right)}$$

$\approx \cos(\Delta mt)$

$$\Delta\Gamma \sim 0$$

